Form PTO-1449

NEORMATION DISCLOSURE CITATION PE, IN AN APPLICATION

(Use several sheets if necessary)

Docket Number 356952000304

Application Number 09/928,194

Applicant

K. E. PETERSON et al.

Filing Date August 17, 2001

Group Art Unit To Be Assigned

Mailing Date

September 14, 2001

PRATE TRACE HEAL

U.S. PATENT DOCUMENTS

Examiner Initials	Ref. No.	Date	Document No.	Name	Class	Subclass	Filing Date If Appropriate
pn.	1.	03/1988	4,730,496	Knecht et al.			/
pm	2.	10/1991	5,060,526	Barth et al.			
pn	3.	07/1992	5,132,658	Dauenhauer et al.			
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pr	5.	01/1993	5,179,499	MacDonald et al.			
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pv	7.	08/1993	5,235,187	Arney et al.		/	·
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un-	23.	10/1996	5,565,625	Howe et al.			
nn	24.	10/1996	5,567,880	Yokota et al.			

EXAMINER:

Donghee Kang

DATE CONSIDERED:

8-28-62

EXAMINER: Initial if citation considered, whether or not the citation conforms with MPEP 609. Draw a line through the citation if not in conformance and not considered. Include a copy of this form with next communication to applicant.

Application Number 09/928,194

Form PTO-1449 Applicant INFORMATION DISCLOSURE CITATION K. E. PETERSON et al. IN AN APPLICATION (Use several sheets if necessary) Group Art Unit To Be Assigned Filing Date August 17, 2001 SEP 2 0 2001 Mailing Date September 14, 2001 12/1996 5,587,601 Kurtz Jakobsen et al. 26. 01/1997 5,591,679 nn 27. 5,594,171 Ischida et al. 01/14/97 nn 28. 03/1997 5,615,143 MacDonald et al. un pun 29. 05/1997 5,627,427 Das et al. 30. 5,628,917 nr 05/1997 MacDonald et al. nnv 31. Hofmann et al. 06/1997 5,637,539 FOREIGN PATENT DOCUMENTS Ref. Document No. Subclass Translation Examiner Date Country Class **Initials** No. YES NO 5/1990 32. 0 368 446 **EPO** hn 33. 3/1994 0588371 **EPO** nn 34. 4/1994 0591554 **EPO** nhu 35. 7/1994 0 605 300 **EPO** mn 36. 8/1994 94/18697 **PCT** nnh 37. 3/1996 96/08036 **PCT** mn 38. 1/1997 97/01221 **PCT** nnu nuc 39. 2/1997 97/04283 **PCT** nhu 40. 12/8/94 94/28427 **PCT** 4/23/79 5451490 41. Japan nh OTHER DOCUMENTS (including author, title, Date, Pertinent Pages, Etc.) Ref. Title Examiner **Initials** No. V. A. Yunkin et al., "Highly Anisotropic Selective Reactive Ion Etching of Deep Trenches in 42. hnn Silicon", Elsevier Science B. V., Microelectronic Engineering, vol. 23 (1994) pp. 373-376. Ammar, Elie S. and Rodgers, T.J., "UMOS Transistors on (110) Silicon", IEEE Transactions on 43. BM Electron Devices, Vol. Ed-27, No. 5 (1980) nn Goodenough, Frank, "Redesigned Surface-Micromachined Accelerometer IC Provides Increased 44. DATE CONSIDERED: 8-28-02 Donghee King **EXAMINER:** EXAMINER: Initial if citation considered, whether or not the citation conforms with MPEP 609. Draw a line through the citation if not in conformance and not considered. Include a copy of this form with next communication to applicant.

Docket Number 356952000304

Application Number 09/928,194 Docket Number 356952000304 **Form PTO-1449** Applicant INFORMATION DISCLOSURE CITATION K. E. PETERSON et al. IN AN APPLICATION (Use several sheets if necessary) Filing Date August 17, 2001 Group Art Unit To Be Assigned SEP 2 0 2001 Mailing Date September 14, 2001 Sensitivity of +1-5 G Full Scale", Electronic Design, Technology Advances (1995) pgs. 37, 40 CONTRIBACE Sherman, S.J. et al., "A Low Cost Monolithic Accelerometer; Product/Technology Update", IEEE 45. Technical Digest, (1992) pgs. 501-504 phu 46. PCT Written Opinion dated 2/20/97 which relates to International Application No. PCT/US96/07605 nn which corresponds to U.S. Application Serial No. 08/449,140 Y. Uenishi et al., "Micro-Opto-Mechanical Devices Fabricated By Anisotropic Etching of (110) 47. nnu Silicon," Proceedings of the IEEE, Micro Electro Mechanical Systems, 1994, pp. 319-324. K. Petersen, "Silicon as a Mechanical Material," Proceedings of the IEEE, vol. 70, no. 5, 5/82, pp. 48. um 420-457. A. Goyal et al., "Formation of Silicon Reentrant Cavity Heat Sinks Using Anisotropic Etching and 49. nnc Direct Wafer Bonding", IEEE Electron Device Letters, vol. 14, no. 1, 1/93, pp. 29-32. K. Suzuki, "Single Crystal Silicon Micro-Actuators," IEEE Electronic Devices Technical Digest, 50. International Electron Devices Meeting, 1990, pp. 625-628. nha K. Petersen et al., "Surface Micromachined Structures Fabricated with Silicon Fusion Bonding", 51. nny IEEE, 1991, pp. 397-399. J. Bartha et al., "Low Temperature Etching if Si in High Density Plasma Using SF₆/O₂," Elsevier 52. unu Science B. V., MicroElectronic Engineering, vol. 27, 1995, pp. 453-456. C. Fung et al., "Deep Etching of Silicon Using Plasma", Micromachining and Micropackaging of 53. nnh Transducers, Elsevier Science Publishers B. V., 1985, pp. 159-164. C. Linder et al., "Deep Dry Etching Techniques as a New IC Compatible Tool for Silicon 54. nh Micromachining", IEEE, 1991, pp. 524-527. J. Bryzek et al., "Micromachines on the March," IEEE Spectrum, 5/94, pp. 20-31. 55. nn

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PTO/SB/08 (2-92) Sheet 1 of 1

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Form PTO-1449	Docket Number 356952000304	Application Number 09/928,194		
INFORMATION DISCLOSCITE CITA				
IN AN APPLICATION	Kurt E. P	Kurt E. PETERSEN et al.		
(Use several sheets if necessary)	Filing Date August 11, 2001	Group Art Unit 2811		
	Mailing Date January 11, 2002	-		

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nh	2.	7/4/00	6,084,257A	Petersen et al.			
nr	3.	11/13/01	6,316,796B1	Petersen et al.			

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Examiner Initials	Ref. No.	Date	Document No.	Country	Class	Subclass	Translation YES NO

OTHER DOCUMENTS

(including author, title, Date, Pertinent Pages, Etc.)

Examiner Initials	Ref. No.	Title	
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